

 $V_{DS} = 1200 V$

 $R_{DS(on)} = 160 \text{ m}\Omega$

 $I_D@25^{\circ}C = 18 A$

Features

- High Blocking Voltage with Low On-Resistance
- High Speed Switching with Low Capacitance
- Easy to Parallel and Simple to Drive

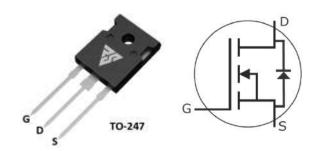
Benefits

- Higher System Efficiency
- Reduced Cooling Requirements
- Increased Power Density
- Increased System Switching Frequency

Applications

- Power Supplies
- High Voltage DC/DC Converters
- Motor Drives
- Switch Mode Power Supplies
- Pulsed Power applications

Package



Part Number	Package
RSM120160W	TO-247-3

REV: AO MAY. 2022

Maximum Ratings (T_c=25°C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
V_{DSmax}	Drain-Source Voltage	1200	V	V V _{GS} =0V, I _D =100μA	
V_{GSmax}	Gate-Source Voltage	-10/+25	0/+25 V Absolute maximum va		
V_{GSop}	Gate-Source Voltage	-5/+20	٧	Recommended operational values	
	Continuous Drain Current	18	A	V _{GS} =20V, T _c =25°C	
I _D		12		V _{GS} =20V, T _c =100°C	
I _{D(pulse)}	Pulsed Drain Current	40	Α	Pulse width t _p limited by T _{Jmax}	
P _D	Power Dissipation	125	W	T _c =25°C, T _J =150°C	
T _J , T _{STG}	Operating Junction and Storage Temperature	-55 to +150	°C		



Electrical Characteristics (T_c=25°C unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note	
V _{(BR)DSS}	Drain-Source Breakdown Voltage	1200	/	/	V	V _{GS} =0V, I _D =100μA		
V	0. 7	2.0	2.4	4.0	V	V _{DS} =V _{GS} , I _D =2.5mA	Eig 11	
$V_{GS(th)}$	Gate Threshold Voltage	/	1.8	/	V	$V_{DS}=V_{GS}$, $I_D=2.5$ mA, $T_J=150$ °C	Fig. 11	
I _{DSS}	Zero Gate Voltage Drain Current	/	1	100	μΑ	V _{DS} =1200V, V _{GS} =0V		
I _{GSS+}	Gate-Source Leakage Current	/	10	250	nA	V _{DS} =0V, V _{GS} =25V		
I _{GSS-}	Gate-Source Leakage Current	/	10	250	nA	V _{DS} =0V, V _{GS} =-10V		
В	Drain-Source On-State Resistance	/	160	196	mΩ	V _{GS} =20V, I _D =10A	Fig.	
R _{DS(on)}	Drain-Source On-State Resistance	/	280	/	11152	V _{GS} =20V, I _D =10A, T _J =150°C	4,5,6	
C _{iss}	Input Capacitance	/	890	/		V _{GS} =0V	Fia	
C _{oss}	Output Capacitance	/	54	/	рF	V _{DS} =1000V	Fig. 15,16	
C_{rss}	Reverse Transfer Capacitance	/	8.5	/		f=1MHz	15,10	
E _{oss}	C _{oss} Stored Energy	/	31	/	μ	V _{AC} =25mV		
E _{ON}	Turn-On Switching Energy	/	315	/	1	V _{DS} =800V, V _{GS} =-5V/20V		
E _{OFF}	Turn-Off Switching Energy	/	63	/	μ	I_D =10A, $R_{G(ext)}$ =2.5Ω, L=200μH		
t _{d(on)}	Turn-On Delay Time	/	8	/				
t _r	Rise Time	/	9	/	ns	V _{DS} =800V, V _{GS} =-5V/20V, I _D =10A		
$t_{d(off)}$	Turn-Off Delay Time	/	14	/	ns	$R_{G(ext)}$ =2.5 Ω , R_L =80 Ω		
t_f	Fall Time	/	9	/				
R _{G(int)}	Internal Gate Resistance	/	5.5	/	Ω	f=1MHz, V _{AC} =25mV		
\mathbf{Q}_{GS}	Gate to Source Charge	/	17	/		V _{DS} =800V		
\mathbf{Q}_{GD}	Gate to Drain Charge	/	9	/	nC	V _{GS} =-5V/20V		
\mathbf{Q}_{G}	Total Gate Charge	/	49	/		I _D =10A		

Reverse Diode Characteristics

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
V	Diode Forward Voltage	4.2	/	V	V _{GS} =-5V, I _{SD} =5A	Fig.
V _{SD}		3.9	/		V _{GS} =-5V, I _{SD} =5A, T _J =150°C	8,9,10
Is	Continuous Diode Forward Current	/	23	Α	T _C =25°C	
t _{rr}	Reverse Recover Time	28	/	ns		
Q _{rr}	Reverse Recovery Charge	50	/	nC	V _R =800V, I _{SD} =10A	
I _{rrm}	Peak Reverse Recovery Current	3	/	Α		

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	0.9	/	°C/W		
$R_{\theta JA}$	Thermal Resistance from Junction to Ambient	/	40	C/W		



Typical Performance

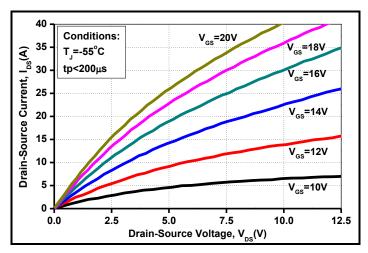


Figure 1. Output Characteristics T_J= -55 °C

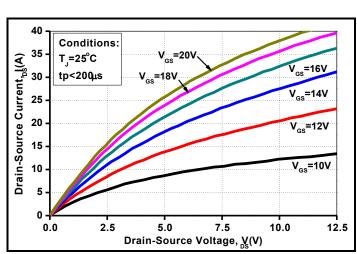


Figure 2. Output Characteristics T_J = 25 °C

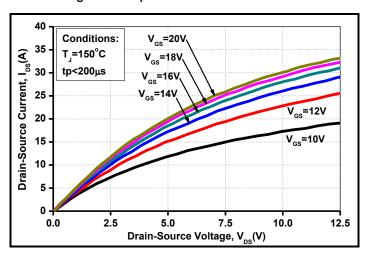


Figure 3. Output Characteristics T_J = 150 °C

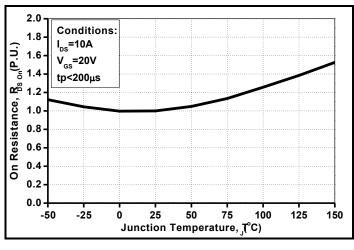


Figure 4. Normalized On-Resistance vs. Temperature

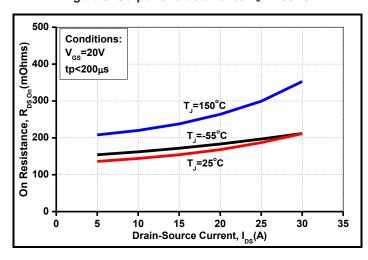


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

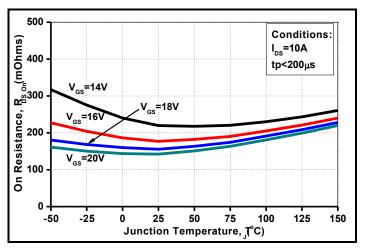


Figure 6. On-Resistance vs. Temperature
For Various Gate Voltage



Typical Performance

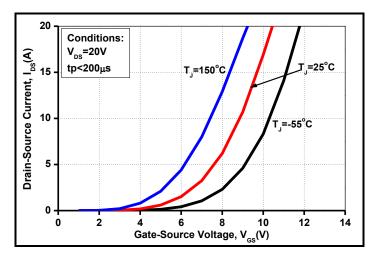


Figure 7. Transfer Characteristic for Various Junction Temperatures

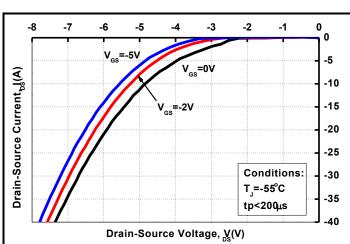


Figure 8. Body Diode Characteristic at -55 °C

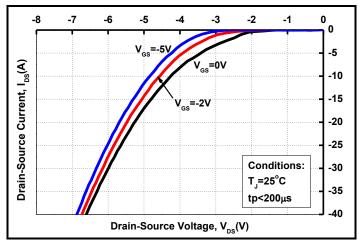


Figure 9. Body Diode Characteristic at 25 °C

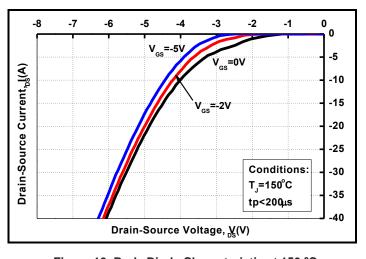


Figure 10. Body Diode Characteristic at 150 °C

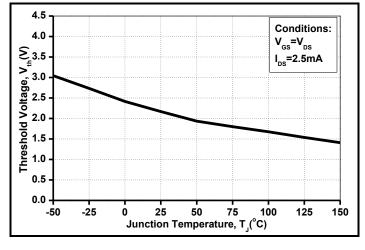


Figure 11. Threshold Voltage vs. Temperature

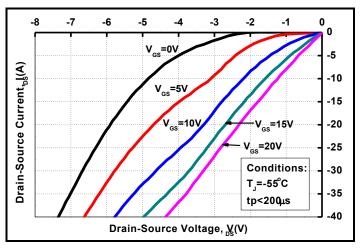
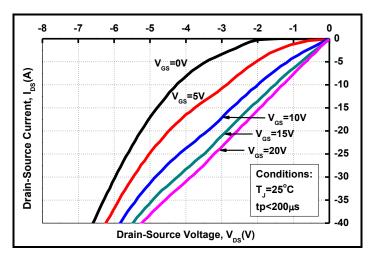


Figure 12. 3rd Quadrant Characteristic at -55 °C



Typical Performance



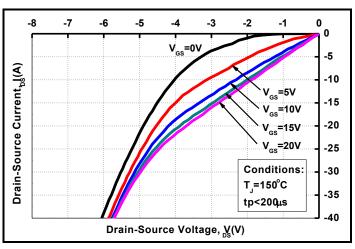
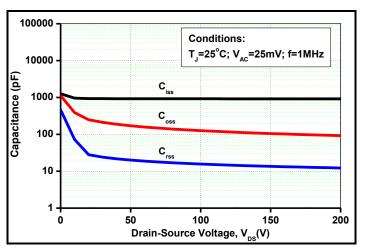


Figure 13. 3rd Quadrant Characteristic at 25 °C





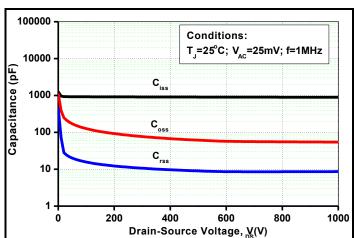


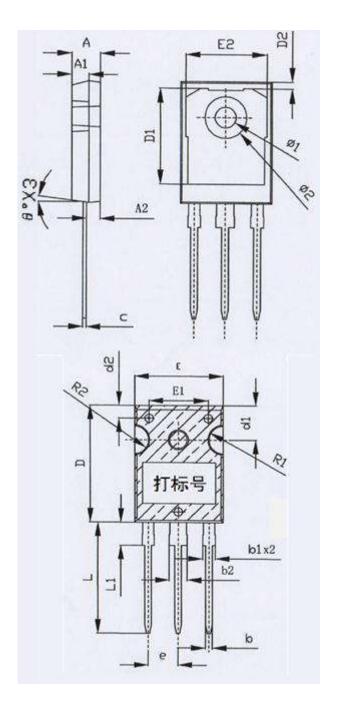
Figure 15. Capacitances vs. Drain-Source Voltage (0 - 200V)

Figure 16. Capacitances vs. Drain-Source Voltage (0 - 1000V)



Package Dimensions

Package TO-247-3



SYMBOLS	DIMENSIONS IN					
	MILLMETERS MIN NOM MAX					
	MIN	MAX				
Α	4.9	5	5.1			
A1	2.9	3	3.1			
A2	2.31	2.36	2.41			
b	1.16	1.2	1.26			
b1	2.05	-	2.2			
b2	3.05	-	3.2			
С	0.58	0.6	0.66			
D	20.9	21	21.1			
D1	16.46	16.56	16.76			
D2		1.17				
d1	6.05	6.15	6.25			
d2	2.2	2.3	2.4			
E	15.7	15.8	15.9			
E1		10.5				
E2		14.02				
е	-	1.27bcs	ı			
L	19.82	19.92	20.02			
L1	1.88	1.98	2.08			
θ	0°	7°	8°			
R1	-	2.7				
R2	-	2.5	-			
Ф1		3.6				
Ф2	-	7.19	-			



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